OIPE
JAN 23 2002
PATENT & TRADEMARK OFFICE

#39
6-10-02

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 09/854,177
Filed: May 10, 2001
Inventor(s):
Xu et al.

Title: METHOD AND SYSTEM FOR DETECTING METAL CONTAMINATION ON A SEMICONDUCTOR WAFER

Examiner: Unknown
Group/Art Unit: 2812
Atty. Dkt. No: 5589-00501

CERTIFICATE OF MAILING
37 C.F.R. § 1.8

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to Commissioner for Patents, Washington, DC 20231, on the date indicated below.

Pam W. Gerik
Printed Name

Pam Gerik
Signature

November 2, 2001
Date

PRELIMINARY AMENDMENT

OF PAPERS
ORIGINALLY FILED

Commissioner for Patents
Washington, D.C. 20231

Sir:

Please amend the above-captioned application as follows:

In the Claims:

Please cancel claims 48-54, 56-64, 66-98, 100-132, 134-151, 153-169, 171-187, 189-205, and 207-240 without prejudice.

Claims 1-47, 55, 65, 99, 133, 152, 170, 188, and 206 remain pending in the captioned case.